



Workshop by IEEE Ottawa Section I&M Society Chapter In conjunction with IEEE Ottawa Section PES/RS Chapters, EA, and EPMG of INMS/NRC

The IEEE Ottawa Section, with Electrical Power Measurements Group of NRC, is organizing a workshop on Instrumentation & Measurements for IEEE members. Non-members interested in the subject are also welcome.

The Future of Instrumentation and Measurement Today's Trends and Future Directions

Speakers from Industry, Research Institutions and Academia

DATE: Wednesday, February 22, 2006

TIME: Registration, Networking, and Coffee/Pastry: 8:00 - 8:30 a.m.; Workshop: 8:30 am - 4:30 pm

Buffet Lunch 12:15 p.m. – 1:00 p.m. Coffee breaks 10:15 – 10:35 a.m. and 2:20 – 2:40 p.m.

PLACE: National Research Council, 1200 Montreal Road, Ottawa, Building M-50, Auditorium.

PARKING: No fee at the visitor's parking. Please respect restricted areas.

Presentations/Speakers

• Moderator: Gerry Turcotte, former Communications Research Centre President,

- Opening Address "Metrology for Canadians, Now and in the Future," by Dr. James McLaren, Director General, Institute for National Measurement Standards, NRC,
- Keynote Address "Intelligent Sensor Agents for Infrastructure and Environment Monitoring - Challenges," by Dr. Emil Petriu, Acting Dean, Faculty of Engineering, University of Ottawa,
- **I&M Industry Trends**, by Larry Desjardin, Strategic Planning Manager, Agilent Technologies, Santa Rosa, CA
- Embedded Testing of VLSI / Systems on a Chip, by Jeff Rearick, Scientist, Agilent Technologies, Fort Collins, CO,
- Optical Heterodyne Instruments in Optical Communications, by Dr. Bogdan Szafraniec, Agilent Technologies, Palo Alto, CA,
- **Microwave antenna measurement at CRC**, by David Lee, Advanced Antenna Technology Research Group, Communications Research Centre of Canada,
- Fast and Selective Detection of Chemical and Biological Agents using Ion Mobility and Mass Spectrometry, by Dr. Zoltan Mester, Institute for National Measurement Standards, National Research Council of Canada,
- **LXI Interface Standard / Synthetic Instruments**, by Grant Drenkow, Solution Planner, System Components, Agilent Technologies, Loveland, CO,
- Military Applications of High Performance Data Acquisition and Signal Processing Systems, by Robert Inkol, Defense Research and Development Canada,

Attend this IEEE Workshop and Earn 0.65 CEUs!

- Continuing Education Units as evaluated by the Engineering Institute of Canada -

Admission: Special Discount for IEEE I&M Society Members: \$20

IEEE/IEE/PEO Members: \$80 Members Retired / Job Seekers: \$40.00 IEEE/IEE Student Memb.: \$20 Non-members: \$100.00 Non-members Retired / Job Seekers: \$50.00 Non-members Students: \$25.00 Registration at the door: additional \$10. Buffet Lunch and refreshments included in the registration.

For more details, please visit: http://ottawa.ieee.ca/ims/Event.html

To ensure a seat, please register on-line at:

http://www.modasolutions.com/Forms/IEEE_EDUCATION/index19012006.htm